U.S. PATENT ATTY. DOCKET NO. APPLICATION NO. INFORMATION DISCLOSURE 2336-198 10/626,674 CITATION IN AN **APPLICANT APPLICATION** Jong Hwan KIM et al. et al. FILING DATE **GROUP** (PTO-1449) 2681 7685 July 25, 2003 **U.S. PATENT DOCUMENTS** FILING **EXAMINER'S** SUBCLASS **CLASS** NAME DATE PATENT NO. DATE INITIALS FOREIGN PATENT DOCUMENTS Translation **EXAMINER'S CLASS SUBCLASS** COUNTRY DATE PATENT NO. INITIALS \mathbf{X} Korea 4/1998 120590 OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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